

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/552,131 MELKOTE ET AL.	
		Examiner	Art Unit	Page 1 of 1 Anh Ly 2162

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,434,580	08-2002	Takano et al.	715/530
*	B	US-2003/0046307	03-2003	Rivette et al.	707/104.1
*	C	US-2001/0039505	11-2001	Cronin, John E.	705/7
*	D	US-2006/0031092	02-2006	Cronin, John E.	705/001
*	E	US-2002/0087562	07-2002	McAnaney et al.	707/100
*	E	US-5,991,780	11-1999	Rivette et al.	715/512
*	G	US-2004/0103112	05-2004	Colson et al.	707/102
*	H	US-2001/0049707	12-2001	Tran, Bao Q.	707/530
*	I	US-2007/0299683	12-2007	Elliott, Douglas R.	705/001
*	J	US-2006/0224412	10-2006	Frank et al.	705/001
*	K	US-6,157,947	12-2000	Watanabe et al.	709/217
*	L	US-2007/0299683	12-2007	Elliott, Douglas R.	705/001
*	M	US-2007/0078886	04-2007	Rivette et al.	707/102

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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